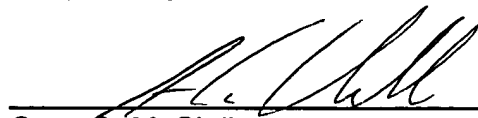


In accordance with 37 CFR § 1.97, this Information Disclosure Statement is not to be construed as a representation that a search has been made or that no other possibly material information as defined under 37 CFR § 1.56(a) exists.

The patents and/or publications submitted herewith are set forth on the attached Form PTO-1449.

If the sum of \$180.00 is due under 37 CFR § 1.17(p) pursuant to § 1.97, the Commissioner is hereby authorized to charge this fee, and any other fee necessary to make this submission timely, to the Deposit Account No. 20-0782/INFN/0056/GGM.

Respectfully submitted,

A handwritten signature in black ink, appearing to read "G. G. McClellan", is written over a horizontal line.

Gero G. McClellan
Registration No. 44,227
MOSER, PATTERSON & SHERIDAN, L.L.P.
3040 Post Oak Blvd. Suite 1500
Houston, TX 77056
Telephone: (713) 623-4844
Facsimile: (713) 623-4846
Attorney for Applicant(s)



Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number.

Substitute for form 1449B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>				Application Number	Unknown
				Filing Date	Herewith
				First Named Inventor	MARIO DI RONZA
				Group Art Unit	Unknown
				Examiner Name	Unknown
				Attorney Docket Number	INFN/0056
Sheet	1	of	2	Submission Date	

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²
	C1	TARR, ET AL., "Defect analysis system speeds Test and Repair of Redundant Memories," <i>M. Electronics</i> , January 12, 1984, pages 175-179, vol. 57, no. 1, VNU Business Publications, New York, U.S.A.	✓
	C2	GANAPATHY, ET AL., "Yield Modeling and Optimization of Large Redundant RAM's" <i>1990 International Conference on Wafer Scale Integration, WSI Design and Support Technology</i> , pages 273-287, IEEE Comput. Soc.	✓
	C3	DILIP K. BHAVSAR, "An Algorithm for Row-Column Self-Repair of RAMs and Its Implementation in the Alpha 21264" <i>ITC International Test Conference</i> , 1999, pages 311-318, <i>IEEE</i> .	✓
	C4	HEON-CHEOL KIM, "A BISR (Built-In Self-Repair) Circuit for Embedded Memory With Multiple Redundancies" <i>1999 IEEE</i> , pages 602-605.	✓
	C5	European Search Report for Application No. 03002698.3 dated October 1, 2003.	
	C6	Partial European Search Report for Application No. 03002698.3 dated July 23, 2003.	
	C7		
	C8		
	C9		
	C10		
	C11		
	C12		

Examiner

Date Considered

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.



Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number.

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>				Application Number		Unknown	
				Filing Date		Her with	
				First Named Inventor		MARIO DI RONZA	
				Group Art Unit		Unknown	
				Examiner Name		Unknown	
				Attorney Docket Number		INFN/0056	
Sheet	1	of	2	Submission Date			

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
	A1	US- 5,808,945	09/15/1998	ARASE	
	A2	US- 6,026,505	02/15/2000	HEDBERG, ET AL.	
	A3	US- 2002/0108073	08/08/2002	HUGHES	
	A4	US- 6,141,267	10/31/2000	KIRIHATA, ET AL.	
	A5	US- 2002/159305	10/31/2002	YOO, ET AL.	
	A6	US-			
	A7	US-			
	A8	US-			
	A9	US-			
	A10	US-			
	A11	US-			
	A12	US-			
	A13	US-			
	A14	US-			
	A15	US-			
	A16	US-			
	A17	US-			
	A18	US-			

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Number-Kind Code ² (if known)				
	B1					
	B2					
	B3					
	B4					
	B5					

Examiner	Date Considered
----------	-----------------

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO